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# 1 Electrical ratings

**Table 2. Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{DS}$	Drain-source voltage	600	V
$V_{DGR}$	Drain-gate voltage ( $R_{GS} = 20\text{ k}\Omega$ )	600	V
$V_{GS}$	Gate-source voltage	$\pm 30$	V
$I_D$	Drain current (continuous) at $T_C = 25^\circ\text{C}$	13.5	A
$I_D$	Drain current (continuous) at $T_C = 100^\circ\text{C}$	8.5	A
$I_{DM}^{(1)}$	Drain current (pulsed)	54	A
$P_{TOT}$	Total dissipation at $T_C = 25^\circ\text{C}$	160	W
	Derating factor	1.28	W/ $^\circ\text{C}$
ESD	Gate-source human body model ( $R = 1.5\text{ k}\Omega$ , $C = 100\text{ pF}$ )	4	kV
$dv/dt^{(2)}$	Peak diode recovery voltage slope	4.5	V/ns
$T_J$ $T_{stg}$	Operating junction temperature Storage temperature	-55 to 150	$^\circ\text{C}$

1. Pulse width limited by safe operating area

2.  $I_{SD} \leq 13.5\text{ A}$ ,  $di/dt \leq 200\text{ A}/\mu\text{s}$ ,  $V_{DD} \leq V_{(BR)DSS}$ ,  $T_J \leq T_{JMAX}$ .

**Table 3. Thermal data**

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case max	0.78	$^\circ\text{C}/\text{W}$
$R_{thj-amb}$	Thermal resistance junction-ambient max	62.5	$^\circ\text{C}/\text{W}$

**Table 4. Avalanche characteristics**

Symbol	Parameter	Value	Unit
$I_{AS}$	Avalanche current, repetitive or not-repetitive (pulse width limited by $T_{Jmax}$ )	12	A
$E_{AS}$	Single pulse avalanche energy (starting $T_J = 25^\circ\text{C}$ , $I_D = I_{AR}$ , $V_{DD} = 50\text{ V}$ )	300	mJ

## 2 Electrical characteristics

( $T_{CASE}=25^{\circ}\text{C}$  unless otherwise specified)

Table 5. On/off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$I_D = 1 \text{ mA}$ , $V_{GS} = 0$	600			V
$I_{DSS}$	Zero gate voltage drain current ( $V_{GS} = 0$ )	$V_{DS} = 600 \text{ V}$			1	$\mu\text{A}$
		$V_{DS} = 600 \text{ V}$ , $T_C=125^{\circ}\text{C}$			50	$\mu\text{A}$
$I_{GSS}$	Gate body leakage current ( $V_{DS} = 0$ )	$V_{GS} = \pm 30 \text{ V}$			$\pm 10$	$\mu\text{A}$
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}$ , $I_D = 100 \mu\text{A}$	3	3.75	4.5	V
$R_{DS(on)}$	Static drain-source on resistance	$V_{GS} = 10 \text{ V}$ , $I_D = 6 \text{ A}$		0.45	0.5	$\Omega$

Table 6. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{iss}$	Input capacitance	$V_{DS} = 25 \text{ V}$ , $f = 1 \text{ MHz}$ , $V_{GS} = 0$	-	2220	-	pF
$C_{oss}$	Output capacitance		-	240	-	pF
$C_{rss}$	Reverse transfer capacitance		-	57	-	pF
$C_{oss \text{ eq}}^{(1)}$	Equivalent output capacitance	$V_{GS} = 0$ , $V_{DS} = 0 \text{ V to } 480 \text{ V}$	-	122	-	pF
$Q_g$	Total gate charge	$V_{DD} = 480 \text{ V}$ , $I_D = 12 \text{ A}$ $V_{GS} = 10 \text{ V}$	-	75	-	nC
$Q_{gs}$	Gate-source charge		-	13.2	-	nC
$Q_{gd}$	Gate-drain charge		-	38.6	-	nC

1.  $C_{oss \text{ eq}}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$

Table 7. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD}=300\text{ V}$ , $I_D=6\text{ A}$ , $R_G=4.7\ \Omega$ , $V_{GS}=10\text{ V}$ (see Figure 17)	-	26	-	ns
$t_r$	Rise time		-	18	-	ns
$t_{d(off)}$	Turn-off delay time		-	62	-	ns
$t_f$	Fall time		-	13	-	ns
$t_{r(Voff)}$	Off-voltage rise time	$V_{DD}=480\text{ V}$ , $I_D=12\text{ A}$ , $R_G=4.7\ \Omega$ , $V_{GS}=10\text{ V}$ (see Figure 19)	-	12	-	ns
$t_f$	Fall time		-	9.5	-	ns
$t_c$	Cross-over time		-	22	-	ns

Table 8. Source drain diode

Symbol	Parameter	Test conditions	Min	Typ.	Max	Unit
$I_{SD}$	Source-drain current		-		12	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		48	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD}=12\text{ A}$ , $V_{GS}=0$	-		1.6	V
$t_{rr}$	Reverse recovery time	$I_{SD}=12\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$ , $V_{DD}=50\text{ V}$	-	490		ns
$Q_{rr}$	Reverse recovery charge		-	4.7		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	19.3		A
$t_{rr}$	Reverse recovery time	$I_{SD}=12\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$ , $V_{DD}=50\text{ V}$ , $T_j=150\text{ }^\circ\text{C}$	-	664		ns
$Q_{rr}$	Reverse recovery charge		-	6.8		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	20.5		A

1. Pulse width limited by safe operating area

2. Pulsed: pulse duration=300 $\mu\text{s}$ , duty cycle 1.5%

Table 9. Gate-source Zener diode

Symbol	Parameter	Test conditions	Min	Typ.	Max.	Unit
$V_{(BR)GSO}$	Gate-source breakdown voltage	$I_{GS} = \pm 1\text{mA}$ , $I_D=0$	30	-	-	V

The built-in back-to-back Zener diodes have specifically been designed to enhance the device's ESD capability. In this respect the Zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the usage of external components.

## 2.1 Electrical characteristics (curves)

Figure 2. Safe operating area for I<sup>2</sup>PAK and TO-220

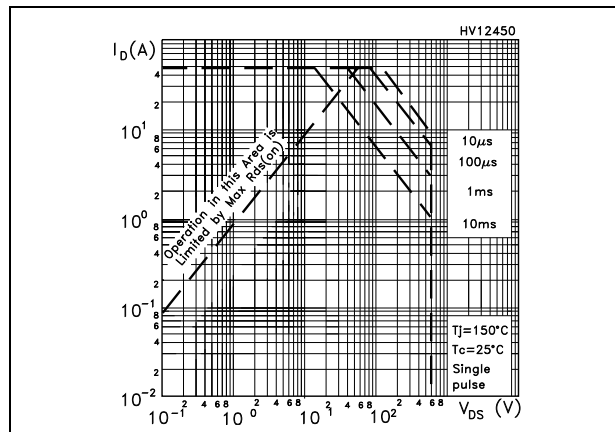


Figure 3. Thermal impedance for I<sup>2</sup>PAK and TO-220

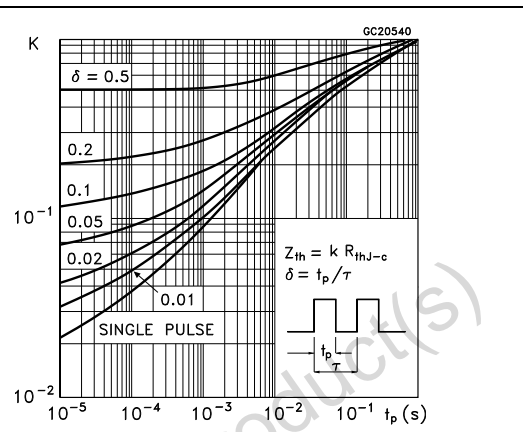


Figure 4. Safe operating area for TO-247

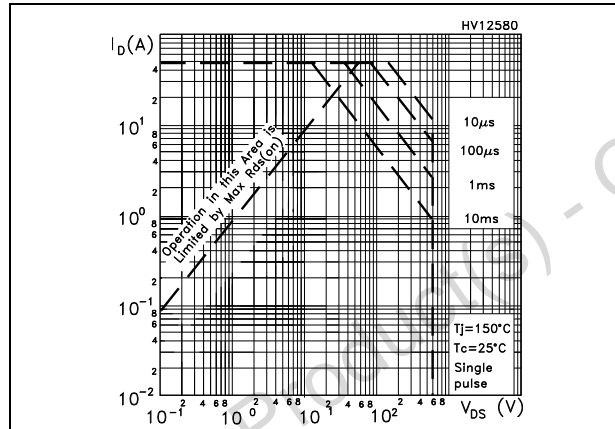


Figure 5. Thermal impedance for TO-247

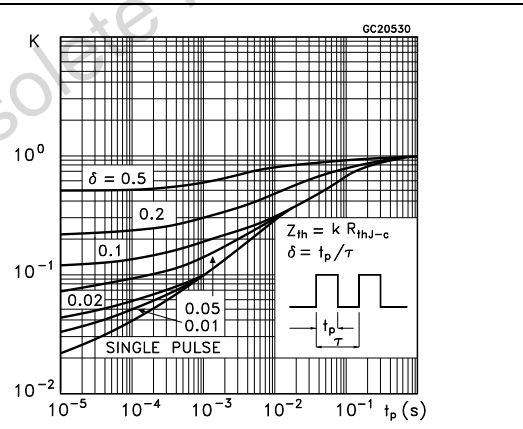


Figure 6. Output characteristics

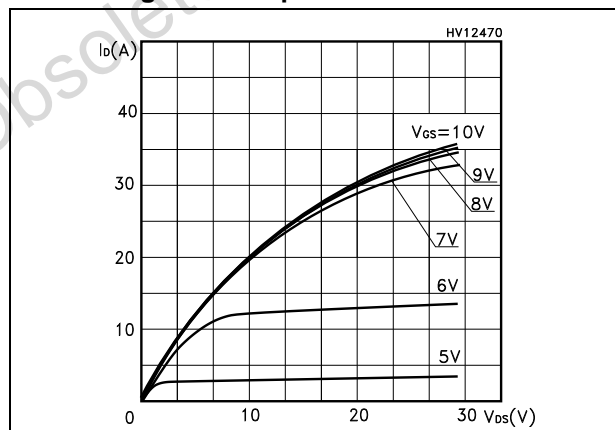


Figure 7. Transfer characteristics

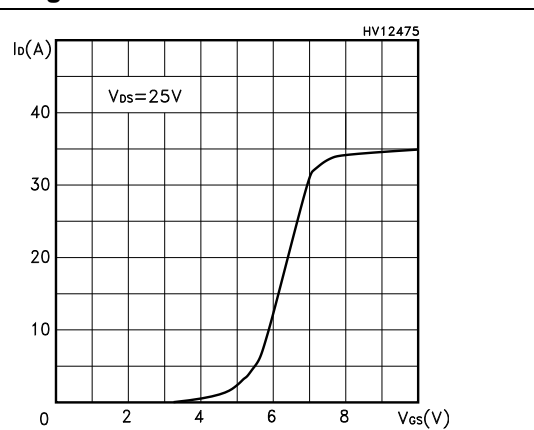


Figure 8. Transconductance

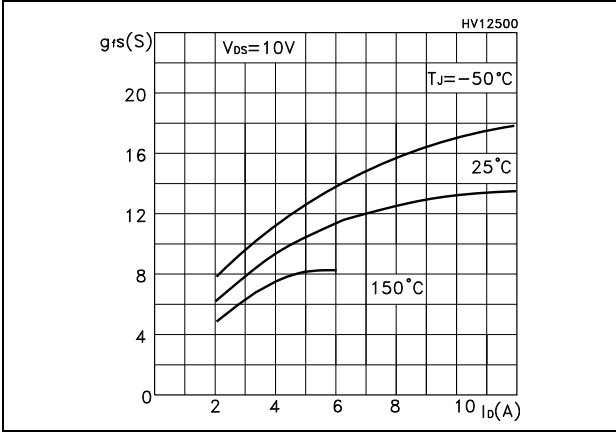


Figure 9. Static drain-source on-resistance

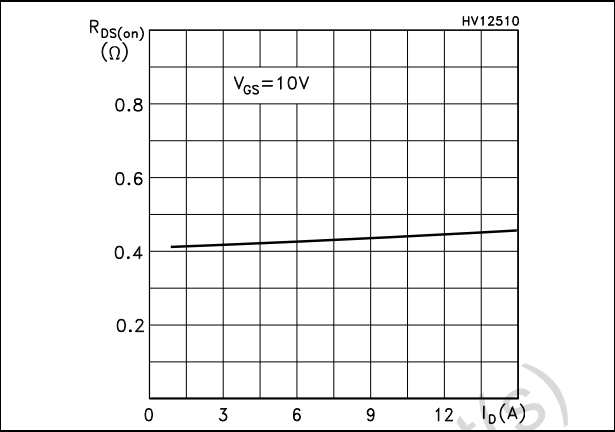


Figure 10. Gate charge vs gate-source voltage

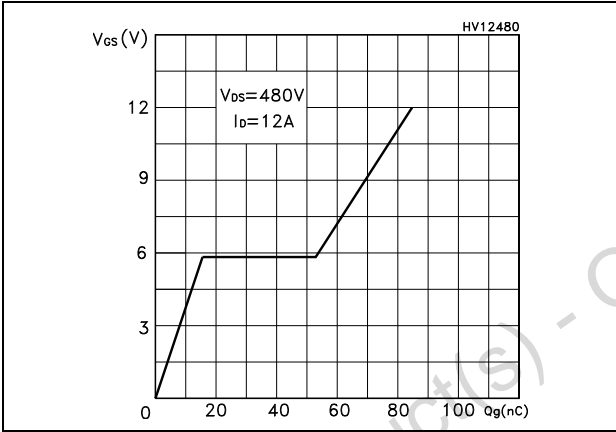


Figure 11. Capacitance variations

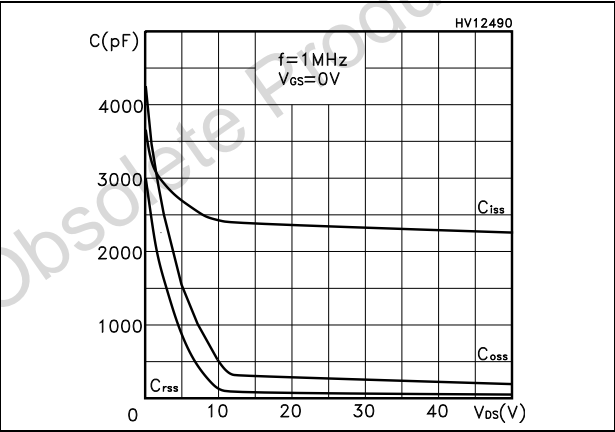


Figure 12. Normalized gate threshold voltage vs temperature

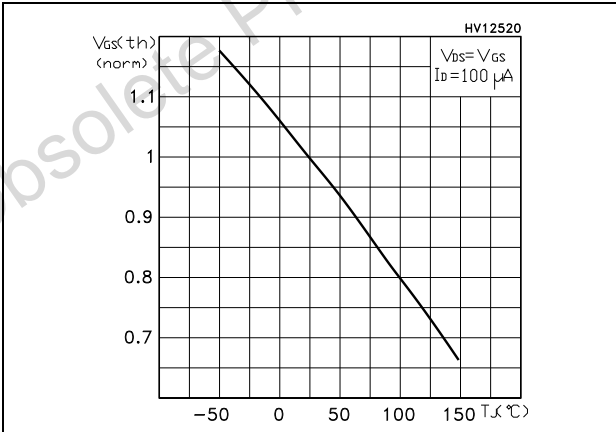


Figure 13. Normalized on-resistance vs temperature

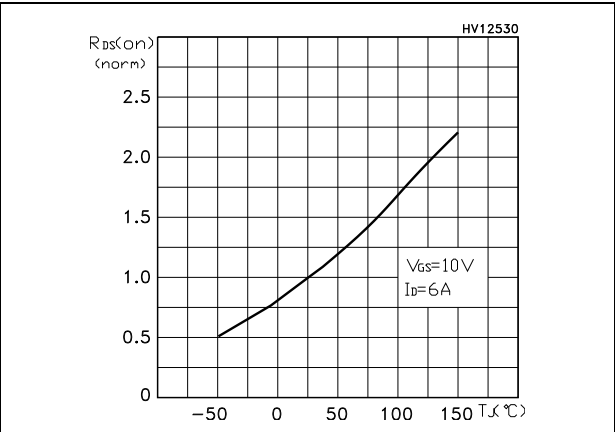


Figure 14. Source-drain diode forward characteristics

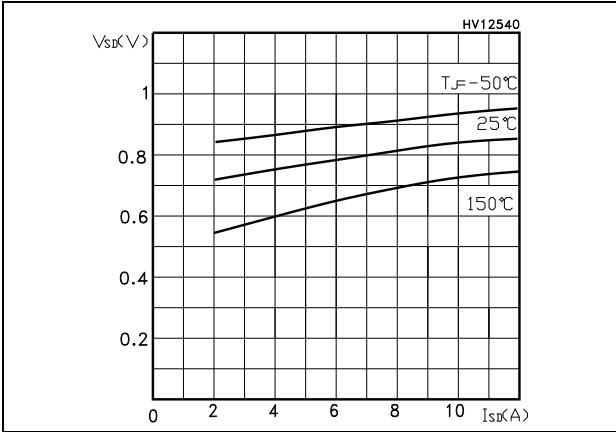


Figure 15. Normalized  $V_{(BR)DSS}$  vs temperature

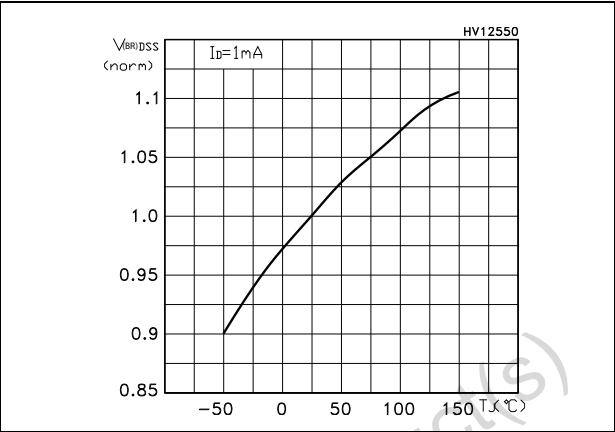
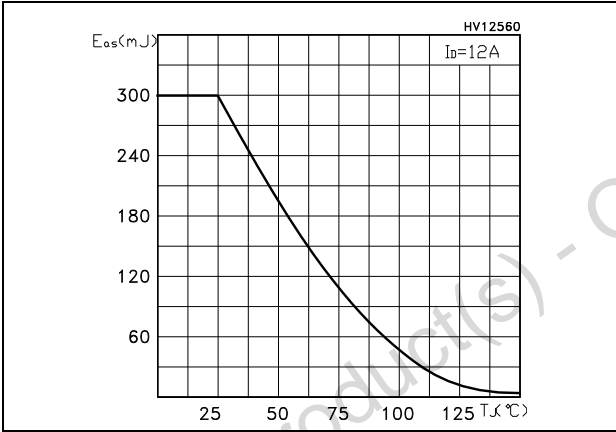


Figure 16. Maximum avalanche energy vs temperature





### 3 Test circuits

Figure 17. Switching times test circuit for resistive load

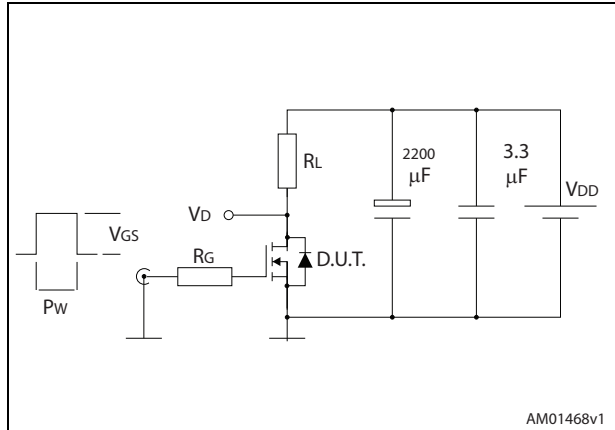


Figure 18. Gate charge test circuit

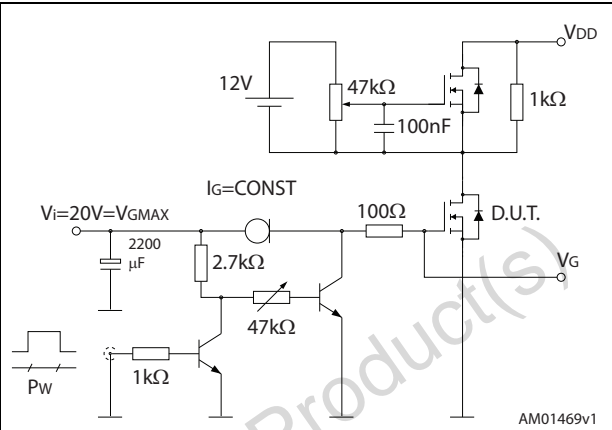


Figure 19. Test circuit for inductive load switching and diode recovery times

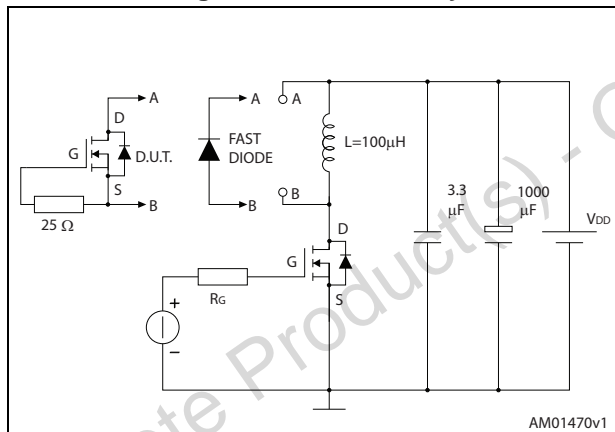


Figure 20. Unclamped inductive load test circuit

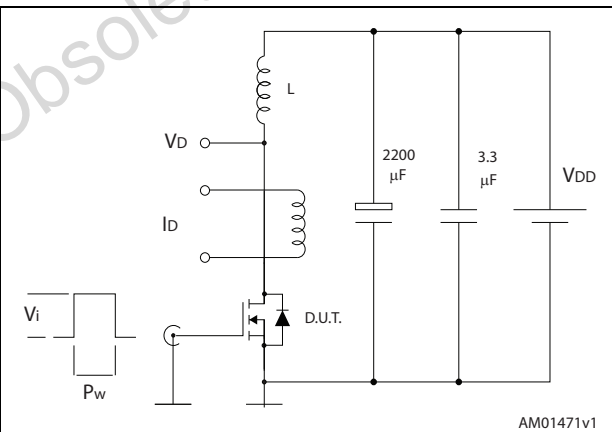


Figure 21. Unclamped inductive waveform

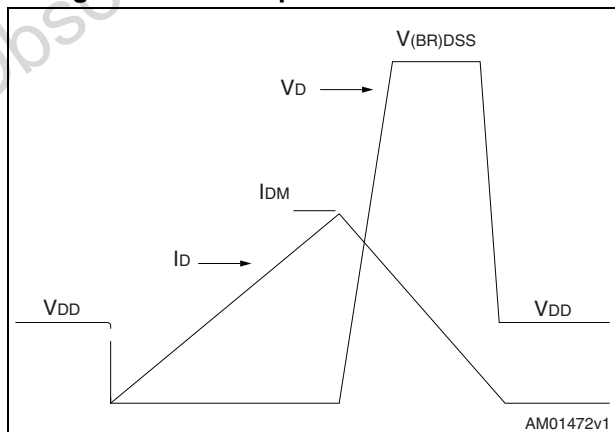
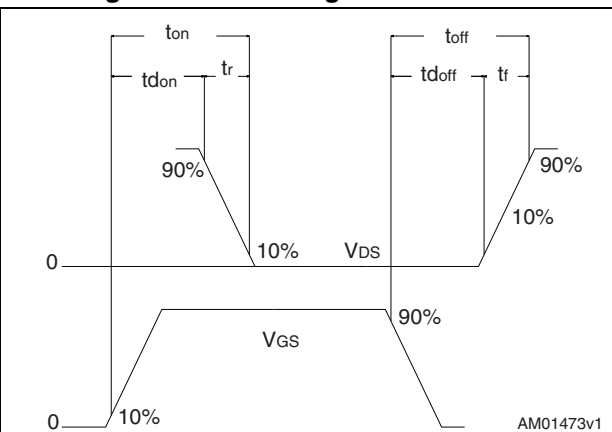


Figure 22. Switching time waveform



## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK<sup>®</sup> packages, depending on their level of environmental compliance. ECOPACK<sup>®</sup> specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com). ECOPACK<sup>®</sup> is an ST trademark.

Obsolete Product(s) - Obsolete Product(s)

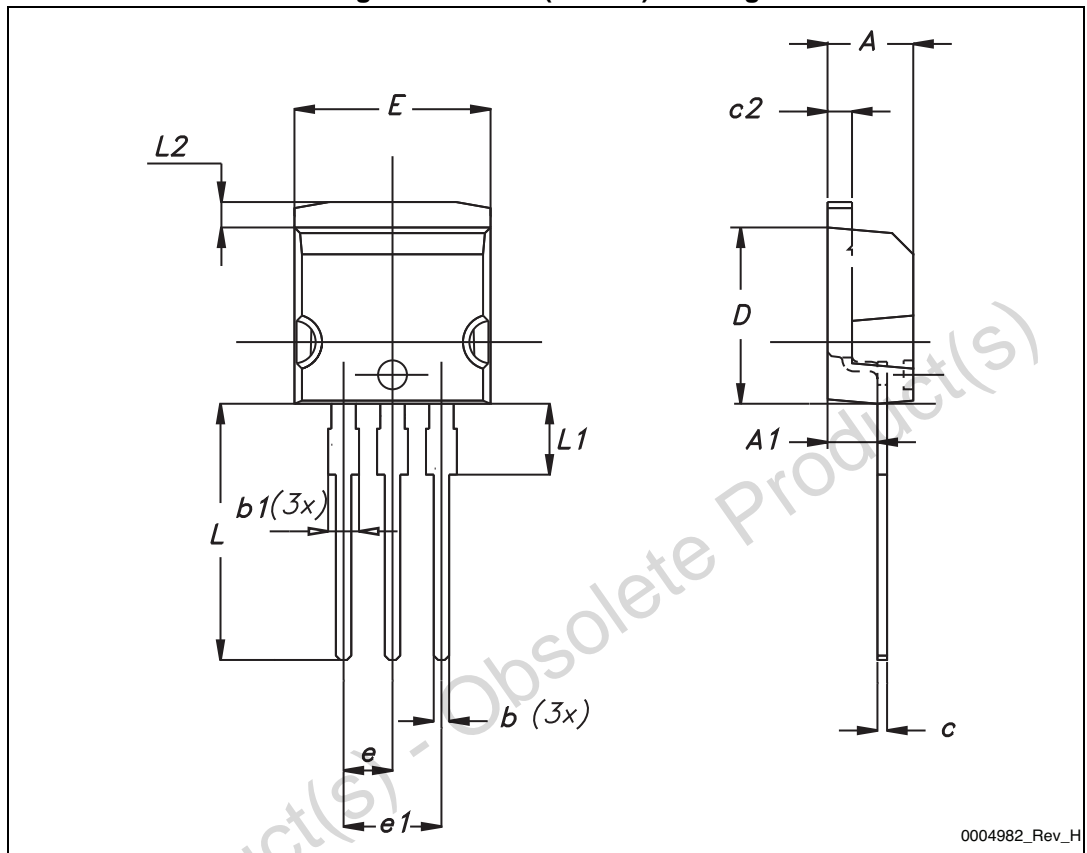
4.1 I<sup>2</sup>PAK, STB14NK60ZFigure 23. I<sup>2</sup>PAK (TO-262) drawing

Table 10. I<sup>2</sup>PAK (TO-262) mechanical data

DIM.	mm.		
	min.	typ	max.
A	4.40		4.60
A1	2.40		2.72
b	0.61		0.88
b1	1.14		1.70
c	0.49		0.70
c2	1.23		1.32
D	8.95		9.35
e	2.40		2.70
e1	4.95		5.15
E	10		10.40
L	13		14
L1	3.50		3.93
L2	1.27		1.40

## 4.2 TO-220, STP14NK60Z

Figure 24. TO-220 type A drawing

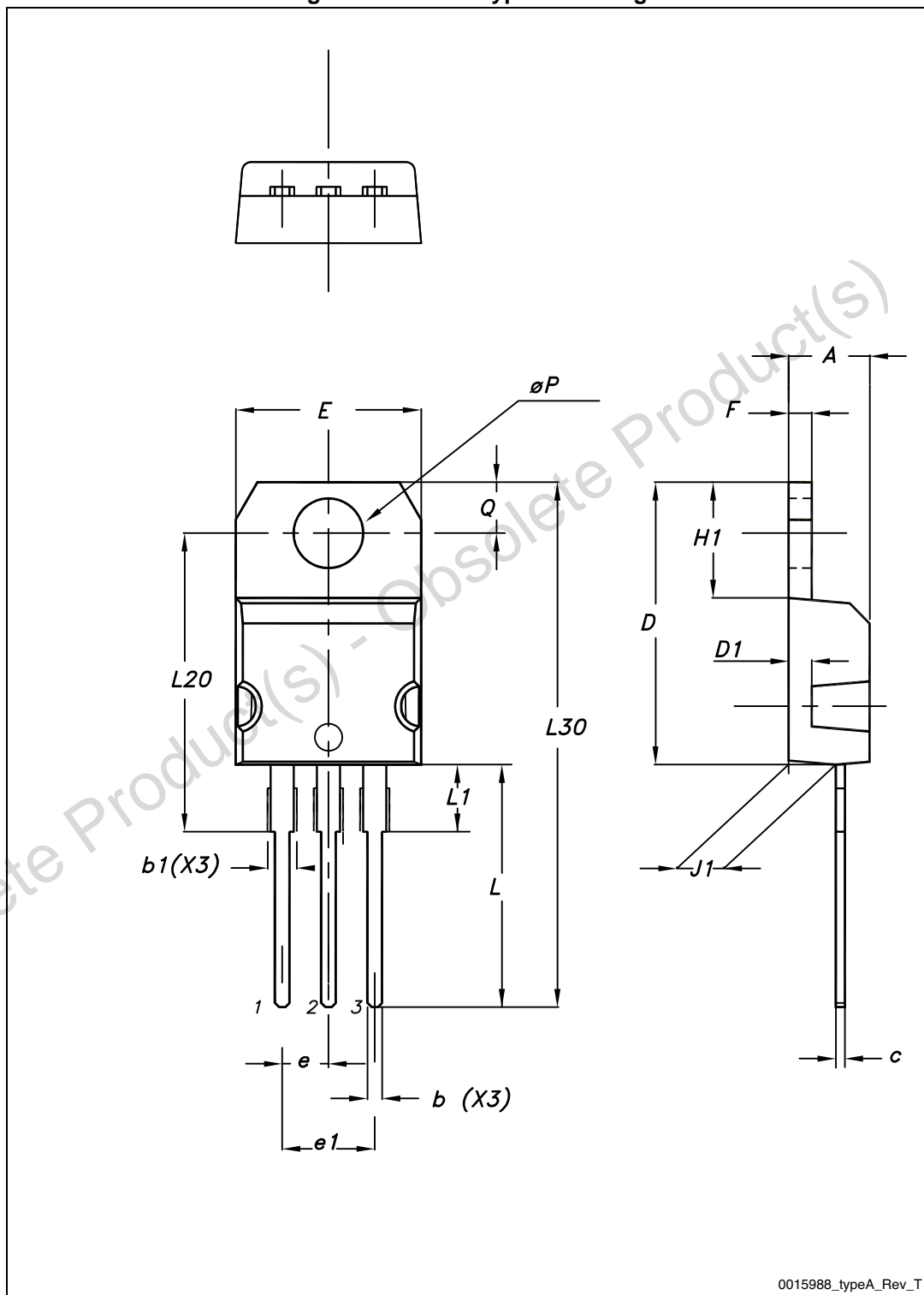


Table 11. TO-220 type A mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.40		4.60
b	0.61		0.88
b1	1.14		1.70
c	0.48		0.70
D	15.25		15.75
D1		1.27	
E	10		10.40
e	2.40		2.70
e1	4.95		5.15
F	1.23		1.32
H1	6.20		6.60
J1	2.40		2.72
L	13		14
L1	3.50		3.93
L20		16.40	
L30		28.90	
ØP	3.75		3.85
Q	2.65		2.95

### 4.3 TO-247, STW14NK60Z

Figure 25. TO-247 drawing

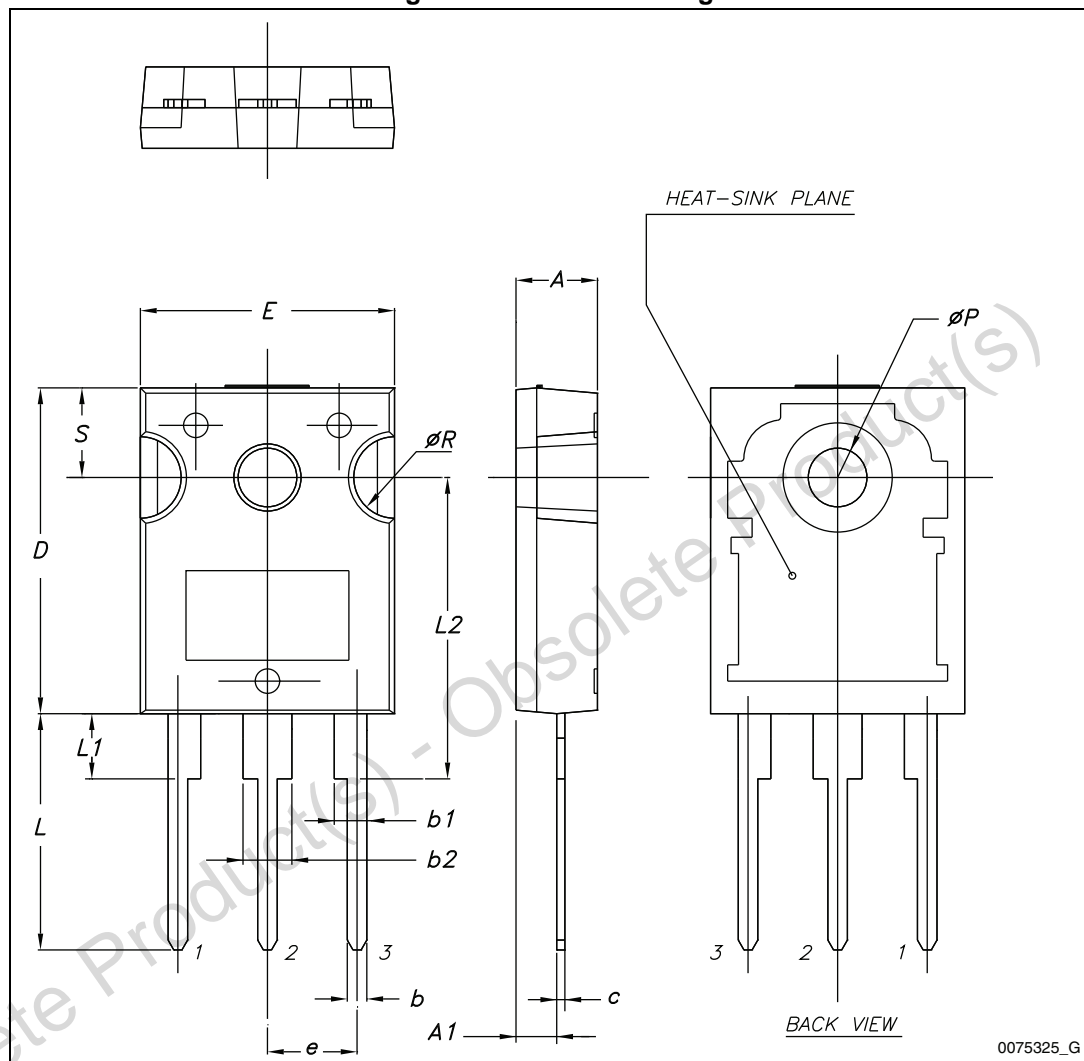


Table 12. TO-247 mechanical data

Dim.	mm.		
	Min.	Typ.	Max.
A	4.85		5.15
A1	2.20		2.60
b	1.0		1.40
b1	2.0		2.40
b2	3.0		3.40
c	0.40		0.80
D	19.85		20.15
E	15.45		15.75
e	5.30	5.45	5.60
L	14.20		14.80
L1	3.70		4.30
L2		18.50	
ØP	3.55		3.65
ØR	4.50		5.50
S	5.30	5.50	5.70



## 5 Revision history

**Table 13. Document revision history**

Date	Revision	Changes
30-Aug-2004	3	Preliminary version
17-Aug-2005	4	Complete version with curves
08-Sep-2005	5	Inserted ecopack indication
14-Oct-2005	6	New package inserted: TO-247
26-Jul-2006	7	New template, no content change
06-May-2014	8	<ul style="list-style-type: none"><li>– Updated: <a href="#">Figure 17</a>, <a href="#">18</a>, <a href="#">19</a> and <a href="#">20</a></li><li>– Updated: <a href="#">Section 4: Package mechanical data</a></li><li>– Minor text changes</li><li>– The part number STP14NK60ZFP has been moved to a separate datasheet</li></ul>

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